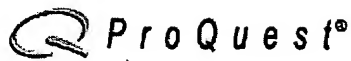


Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	7	"043712".ap.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:44
L2	174	(failure adj prediction).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:46
L3	1	L2 and rve	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:44
L4	50	(failure near2 component same predict\$4).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:46
L5	25	L4 and @ad<"20011025"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:49
L6	0	L5 and volume adj element	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:47
L7	2	rve same component same fail\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:54
L8	0	703/2.ccls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:55
L9	0	703/6.ccls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:55
L10	0	703/7.ccls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:55

L11	0	703/?..cls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:56
L12	40	(microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:56
L13	0	702/?..cls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:57
L14	0	702/34..cls. and (microstructure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:56
L15	3	(micro-structure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:56
L16	0	702/?..cls. and (\$6structure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:57
L17	12	703/?..cls. and (\$6structure same component same fail\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/18 17:57

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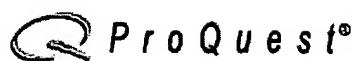
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